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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

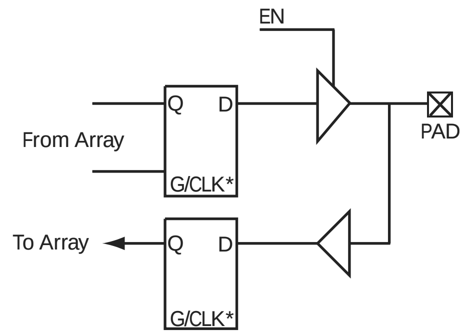
Details	
Product Status	Active
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	83
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	100-BQFP
Supplier Device Package	100-PQFP (20x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a42mx16-pqg100i

Table 1 • **Product profile**

Device	**A40MX02**	**A40MX04**	**A42MX09**	**A42MX16**	**A42MX24**	**A42MX36**
Maximum Flip-Flops	147	273	516	928	1,410	1,822
Clocks	1	1	2	2	2	6
User I/O (maximum)	57	69	104	140	176	202
PCI	–	–	–	–	Yes	Yes
Boundary Scan Test (BST)	–	–	–	–	Yes	Yes
Packages (by pin count)						
PLCC	44, 68	44, 68, 84	84	84	84	–
PQFP	100	100	100, 144, 160	100, 160, 208	160, 208	208, 240
VQFP	80	80	100	100	–	–
TQFP	–	–	176	176	176	–
CQFP	–	–	–	172	–	208, 256
PBGA	–	–	–	–	–	272
CPGA	–	–	132	–	–	–

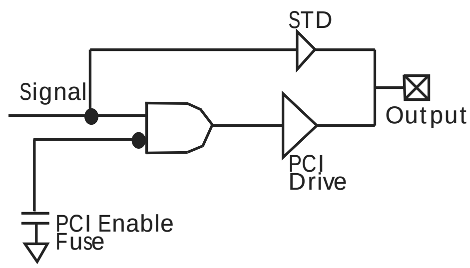
Designer software development tools provide a design library of I/O macro functions that can implement all I/O configurations supported by the MX FPGAs.

Figure 10 • **42MX I/O Module**



Note: **Can be configured as a Latch or D Flip-Flop (Using C-Module)*

Figure 11 • **PCI Output Structure of A42MX24 and A42MX36 Devices**



3.3 Other Architectural Features

The following sections cover other architectural features of 40MX and 42MX FPGAs.

3.3.1 Performance

MX devices can operate with internal clock frequencies of 250 MHz, enabling fast execution of complex logic functions. MX devices are live on power-up and do not require auxiliary configuration devices and thus are an optimal platform to integrate the functionality contained in multiple programmable logic devices. In addition, designs that previously would have required a gate array to meet performance can be integrated into an MX device with improvements in cost and time-to-market. Using timing-driven place-and-route (TDPR) tools, designers can achieve highly deterministic device performance.

3.3.2 User Security

Microsemi FuseLock provides robust security against design theft. Special security fuses are hidden in the fabric of the device and protect against unauthorized users attempting to access the programming and/or probe interfaces. It is virtually impossible to identify or bypass these fuses without damaging the device, making Microsemi antifuse FPGAs protected with the highest level of security available from both invasive and noninvasive attacks.

Special security fuses in 40MX devices include the Probe Fuse and Program Fuse. The former disables the probing circuitry while the latter prohibits further programming of all fuses, including the Probe Fuse. In 42MX devices, there is the Security Fuse which, when programmed, both disables the probing circuitry and prohibits further programming of the device.

3.3.3 Programming

Device programming is supported through the Silicon Sculptor series of programmers. Silicon Sculptor is a compact, robust, single-site and multi-site device programmer for the PC. With standalone software, Silicon Sculptor is designed to allow concurrent programming of multiple units from the same PC.

f_{q2} = Average second routed array clock rate in MHz)

Table 7 • **Fixed Capacitance Values for MX FPGAs (pF)**

Device Type	r1 routed_Clk1	r2 routed_Clk2
A40MX02	41.4	N/A
A40MX04	68.6	N/A
A42MX09	118	118
A42MX16	165	165
A42MX24	185	185
A42MX36	220	220

3.4.6 Test Circuitry and Silicon Explorer II Probe

MX devices contain probing circuitry that provides built-in access to every node in a design, via the use of Silicon Explorer II. Silicon Explorer II is an integrated hardware and software solution that, in conjunction with the Designer software, allow users to examine any of the internal nets of the device while it is operating in a prototyping or a production system. The user can probe into an MX device without changing the placement and routing of the design and without using any additional resources. Silicon Explorer II's noninvasive method does not alter timing or loading effects, thus shortening the debug cycle and providing a true representation of the device under actual functional situations.

Silicon Explorer II samples data at 100 MHz (asynchronous) or 66 MHz (synchronous). Silicon Explorer II attaches to a PC's standard COM port, turning the PC into a fully functional 18-channel logic analyzer. Silicon Explorer II allows designers to complete the design verification process at their desks and reduces verification time from several hours per cycle to a few seconds.

Silicon Explorer II is used to control the MODE, DCLK, SDI and SDO pins in MX devices to select the desired nets for debugging. The user simply assigns the selected internal nets in the Silicon Explorer II software to the PRA/PRB output pins for observation. Probing functionality is activated when the MODE pin is held HIGH.

Figure 12, page 16 illustrates the interconnection between Silicon Explorer II and 40MX devices, while Figure 13, page 17 illustrates the interconnection between Silicon Explorer II and 42MX devices

To allow for probing capabilities, the security fuses must not be programmed. (See User Security, page 12 for the security fuses of 40MX and 42MX devices). Table 8, page 17 summarizes the possible device configurations for probing.

PRA and PRB pins are dual-purpose pins. When the “Reserve Probe Pin” is checked in the Designer software, PRA and PRB pins are reserved as dedicated outputs for probing. If PRA and PRB pins are required as user I/Os to achieve successful layout and “Reserve Probe Pin” is checked, the layout tool will override the option and place user I/Os on PRA and PRB pins.

Figure 12 • **Silicon Explorer II Setup with 40MX**

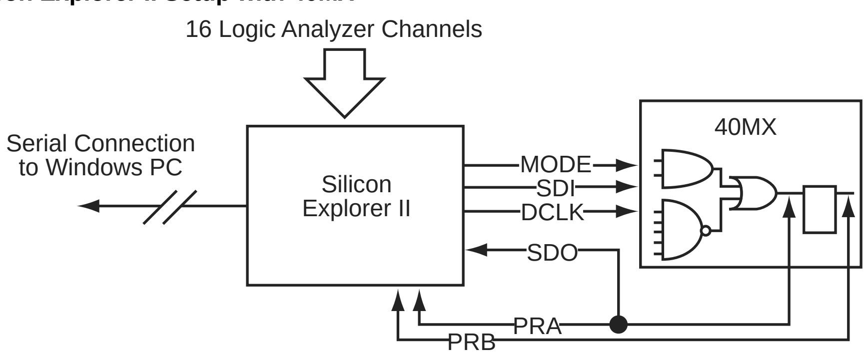
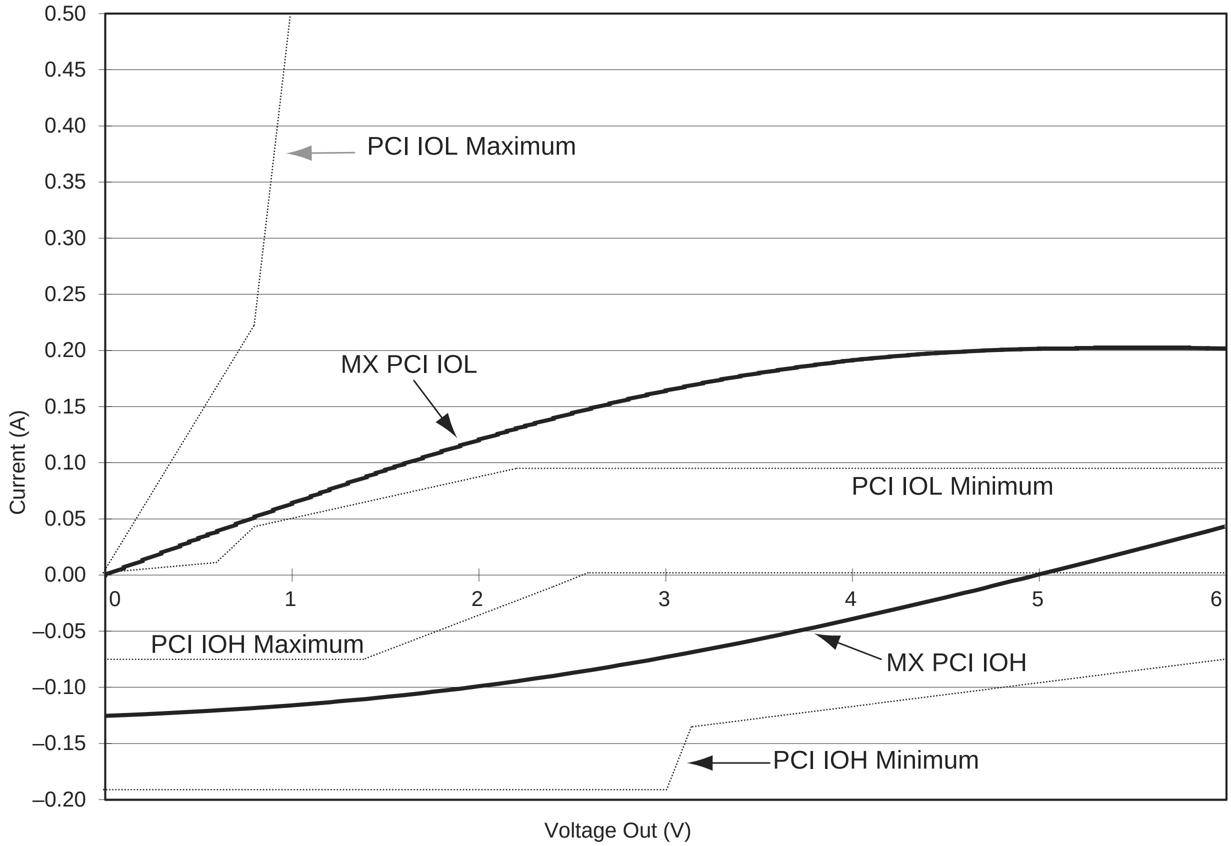


Figure 16 • **Typical Output Drive Characteristics (Based Upon Measured Data)**



3.9.4 Junction Temperature (T_J)

The temperature variable in the Designer software refers to the junction temperature, not the ambient temperature. This is an important distinction because the heat generated from dynamic power consumption is usually hotter than the ambient temperature. The following equation can be used to calculate junction temperature.

$$\text{Junction Temperature} = \Delta T + T_a (1)$$

EQ 4

where:

- T_a = Ambient Temperature
- ΔT = Temperature gradient between junction (silicon) and ambient
- $\Delta T = \theta_{ja} * P$ (2)
- P = Power
- θ_{ja} = Junction to ambient of package. θ_{ja} numbers are located in Table 27, page 29.

3.9.5 Package Thermal Characteristics

The device junction-to-case thermal characteristic is θ_{jc}, and the junction-to-ambient air characteristic is θ_{ja}. The thermal characteristics for θ_{ja} are shown with two different air flow rates.

The maximum junction temperature is 150°C.

Maximum power dissipation for commercial- and industrial-grade devices is a function of θ_{ja}.

Table 37 • **A40MX04 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCC = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
CMOS Output Module Timing[4]												
t_{DLH}	Data-to-Pad HIGH		5.5		6.4		7.2		8.5		11.9	ns
t_{DHL}	Data-to-Pad LOW		4.8		5.5		6.2		7.3		10.2	ns
t_{ENZH}	Enable Pad Z to HIGH		4.7		5.5		6.2		7.3		10.2	ns
t_{ENZL}	Enable Pad Z to LOW		6.8		7.9		8.9		10.5		14.7	ns
t_{ENHZ}	Enable Pad HIGH to Z		11.1		12.8		14.5		17.1		23.9	ns
t_{ENLZ}	Enable Pad LOW to Z		8.2		9.5		10.7		12.6		17.7	ns
d_{TLH}	Delta LOW to HIGH		0.05		0.05		0.06		0.07		0.10	ns/pF
d_{THL}	Delta HIGH to LOW		0.03		0.03		0.04		0.04		0.06	ns/pF

1. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
2. Set-up times assume fanout of 3. Further testing information can be obtained from the Timer utility.
3. The hold time for the DFME1A macro may be greater than 0 ns. Use the Timer tool from the Designer software to check the hold time for this macro.
4. Delays based on 35 pF loading.

Table 38 • **A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.2		1.3		1.5		1.8		2.5	ns
t_{CO}	Sequential Clock-to-Q		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch G-to-Q		1.2		1.4		1.6		1.8		2.6	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		1.2		1.6		1.8		2.1		2.9	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.7		0.8		0.9		1.0		1.4	ns
t_{RD2}	FO = 2 Routing Delay		0.9		1.0		1.2		1.4		1.9	ns
t_{RD3}	FO = 3 Routing Delay		1.2		1.3		1.5		1.7		2.4	ns
t_{RD4}	FO = 4 Routing Delay		1.4		1.5		1.7		2.0		2.9	ns
t_{RD8}	FO = 8 Routing Delay		2.3		2.6		2.9		3.4		4.8	ns
Logic Module Sequential Timing[3, 4]												
t_{SUD}	Flip-Flop (Latch) Data Input Set-Up	0.3		0.4		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.4		0.5		0.5		0.6		0.8		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.4		3.8		4.3		5.0		7.0		ns

Table 40 • **A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)**

Parameter / Description			–3 Speed Min.	–3 Speed Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std Speed Min.	Std Speed Max.	–F Speed Min.	–F Speed Max.	Units
t_{PWL}	Minimum Pulse Width LOW	FO = 32	3.2		3.5		4.0		4.7		6.6		ns
		FO = 384	3.7		4.1		4.6		5.4		7.6		ns
t_{CKSW}	Maximum Skew	FO = 32		0.3		0.4		0.4		0.5		0.7	ns
		FO = 384		0.3		0.4		0.4		0.5		0.7	ns
t_{SUEXT}	Input Latch External Set-Up	FO = 32	0.0		0.0		0.0		0.0		0.0		ns
		FO = 384	0.0		0.0		0.0		0.0		0.0		ns
t_{HEXT}	Input Latch External Hold	FO = 32	2.8		3.1		5.5		4.1		5.7		ns
		FO = 384	3.2		3.5		4.0		4.7		6.6		ns
t_P	Minimum Period	FO = 32	4.2		4.67		5.1		5.8		9.7		ns
		FO = 384	4.6		5.1		5.6		6.4		10.7		ns
f_{MAX}	Maximum Frequency	FO = 32		237		215		198		172		103	MHz
		FO = 384		215		195		179		156		94	MHz

Table 40 • A42MX16 Timing Characteristics (Nominal 5.0 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed Min.	–3 Speed Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std Speed Min.	Std Speed Max.	–F Speed Min.	–F Speed Max.	Units
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		3.2		3.6		4.0		4.7		6.6	ns
t_{DHL}	Data-to-Pad LOW		2.5		2.7		3.1		3.6		5.1	ns
t_{ENZH}	Enable Pad Z to HIGH		2.7		3.0		3.4		4.0		5.6	ns
t_{ENZL}	Enable Pad Z to LOW		3.0		3.3		3.8		4.4		6.2	ns
t_{ENHZ}	Enable Pad HIGH to Z		5.4		6.0		6.8		8.0		11.2	ns
t_{ENLZ}	Enable Pad LOW to Z		5.0		5.6		6.3		7.4		10.4	ns
t_{GLH}	G-to-Pad HIGH		5.1		5.6		6.4		7.5		10.5	ns
t_{GHL}	G-to-Pad LOW		5.1		5.6		6.4		7.5		10.5	ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad), 64 Clock Loading		5.7		6.3		7.1		8.4		11.9	ns
t_{ACO}	Array Clock-to-Out (Pad-to-Pad), 64 Clock Loading		8.0		8.9		10.1		11.9		16.7	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.03		0.03		0.03		0.04		0.06	ns/pF

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, point and position whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. *Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.*
4. Set-up and hold timing parameters for the input buffer latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.
5. Delays based on 35 pF loading

Table 41 • A42MX16 Timing Characteristics (Nominal 3.3 V Operation) (Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		–3 Speed Min.	–3 Speed Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std Speed Min.	Std Speed Max.	–F Speed Min.	–F Speed Max.	Units
Logic Module Propagation Delays[1]												
t_{PD1}	Single Module		1.9		2.1		2.4		2.8		4.0	ns
t_{CO}	Sequential Clock-to-Q		2.0		2.2		2.5		3.0		4.2	ns
t_{GO}	Latch G-to-Q		1.9		2.1		2.4		2.8		4.0	ns
t_{RS}	Flip-Flop (Latch) Reset-to-Q		2.2		2.4		2.8		3.3		4.6	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		1.1		1.2		1.4		1.6		2.3	ns
t_{RD2}	FO = 2 Routing Delay		1.5		1.6		1.8		2.1		3.0	ns
t_{RD3}	FO = 3 Routing Delay		1.8		2.0		2.3		2.7		3.8	ns
t_{RD4}	FO = 4 Routing Delay		2.2		2.4		2.7		3.2		4.5	ns
t_{RD8}	FO = 8 Routing Delay		3.6		4.0		4.5		5.3		7.5	ns

Table 43 • **A42MX24 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
Parameter / Description		**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		2.1		2.0		2.3		2.7		3.7	ns
t_{GO}	Latch Gate-to-Output		3.4		1.9		2.1		2.5		3.4	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.4		0.5		0.6		0.7		0.9		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		2.0		2.2		2.5		2.9		4.1	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.6		0.6		0.7		0.8		1.2		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	4.6		5.2		5.8		6.9		9.6		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	6.1		6.8		7.7		9.0		12.6		ns
Input Module Propagation Delays												
t_{INPY}	Input Data Pad-to-Y		1.4		1.6		1.8		2.2		3.0	ns
t_{INGO}	Input Latch Gate-to-Output		1.8		1.9		2.2		2.6		3.6	ns
t_{INH}	Input Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{INSU}	Input Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{ILA}	Latch Active Pulse Width	6.5		7.3		8.2		9.7		13.5		ns

Table 44 • A42MX36 Timing Characteristics (Nominal 5.0 V Operation)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description		–3 Speed		–2 Speed		–1 Speed		Std Speed		–F Speed		
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Units
Logic Module Combinatorial Functions[1]												
t_{PD}	Internal Array Module Delay		1.3		1.5		1.7		2.0		2.7	ns
t_{PDD}	Internal Decode Module Delay		1.6		1.8		2.0		2.4		3.3	ns
Logic Module Predicted Routing Delays[2]												
t_{RD1}	FO = 1 Routing Delay		0.9		1.0		1.2		1.4		2.0	ns
t_{RD2}	FO = 2 Routing Delay		1.3		1.4		1.6		1.9		2.7	ns
t_{RD3}	FO =3 Routing Delay		1.6		1.8		2.0		2.4		3.4	ns
t_{RD4}	FO = 4 Routing Delay		2.0		2.2		2.5		2.9		4.1	ns
t_{RD5}	FO = 8 Routing Delay		3.3		3.7		4.2		4.9		6.9	ns
t_{RDD}	Decode-to-Output Routing Delay		0.3		0.4		0.4		0.5		0.7	ns
Logic Module Sequential Timing[3, 4]												
t_{CO}	Flip-Flop Clock-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{GO}	Latch Gate-to-Output		1.3		1.4		1.6		1.9		2.7	ns
t_{SUD}	Flip-Flop (Latch) Set-Up Time	0.3		0.3		0.4		0.5		0.7		ns
t_{HD}	Flip-Flop (Latch) Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RO}	Flip-Flop (Latch) Reset-to-Output		1.6		1.7		2.0		2.3		3.2	ns
t_{SUENA}	Flip-Flop (Latch) Enable Set-Up	0.7		0.8		0.9		1.0		1.4		ns
t_{HENA}	Flip-Flop (Latch) Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{WCLKA}	Flip-Flop (Latch) Clock Active Pulse Width	3.3		3.7		4.2		4.9		6.9		ns
t_{WASYN}	Flip-Flop (Latch) Asynchronous Pulse Width	4.4		4.8		5.5		6.4		9.0		ns
Synchronous SRAM Operations												
t_{RC}	Read Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{WC}	Write Cycle Time	6.8		7.5		8.5		10.0		14.0		ns
t_{RCKHL}	Clock HIGH/LOW Time	3.4		3.8		4.3		5.0		7.0		ns
t_{RCO}	Data Valid After Clock HIGH/LOW		3.4		3.8		4.3		5.0		7.0	ns
t_{ADSU}	Address/Data Set-Up Time	1.6		1.8		2.0		2.4		3.4		ns
Synchronous SRAM Operations (continued)												
t_{ADH}	Address/Data Hold Time	0.0		0.0		0.0		0.0		0.0		ns
t_{RENSU}	Read Enable Set-Up	0.6		0.7		0.8		0.9		1.3		ns
t_{RENH}	Read Enable Hold	3.4		3.8		4.3		5.0		7.0		ns
t_{WENSU}	Write Enable Set-Up	2.7		3.0		3.4		4.0		5.6		ns
t_{WENH}	Write Enable Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{BENS}	Block Enable Set-Up	2.8		3.1		3.5		4.1		5.7		ns
t_{BENH}	Block Enable Hold	0.0		0.0		0.0		0.0		0.0		ns

Table 45 • **A42MX36 Timing Characteristics (Nominal 3.3 V Operation) *(continued)*(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)**

Parameter / Description		–3 Speed Min.	–3 Speed Max.	–2 Speed Min.	–2 Speed Max.	–1 Speed Min.	–1 Speed Max.	Std Speed Min.	Std Speed Max.	–F Speed Min.	–F Speed Max.	Units
t_{ACO}	Array Latch Clock-to-Out (Pad-to-Pad) 32 I/O		10.9		12.1		13.7		16.1		22.5	ns
d_{TLH}	Capacitive Loading, LOW to HIGH		0.10		0.11		0.12		0.14		0.20	ns/pF
d_{THL}	Capacitive Loading, HIGH to LOW		0.10		0.11		0.12		0.14		0.20	ns/pF
CMOS Output Module Timing[5]												
t_{DLH}	Data-to-Pad HIGH		4.9		5.5		6.2		7.3		10.3	ns
t_{DHL}	Data-to-Pad LOW		3.4		3.8		4.3		5.1		7.1	ns
t_{ENZH}	Enable Pad Z to HIGH		3.7		4.1		4.7		5.5		7.7	ns
t_{ENZL}	Enable Pad Z to LOW		4.1		4.6		5.2		6.1		8.5	ns
t_{ENHZ}	Enable Pad HIGH to Z		7.4		8.2		9.3		10.9		15.3	ns
t_{ENLZ}	Enable Pad LOW to Z		6.9		7.6		8.7		10.2		14.3	ns
t_{GLH}	G-to-Pad HIGH		7.0		7.8		8.9		10.4		14.6	ns
t_{GHL}	G-to-Pad LOW		7.0		7.8		8.9		10.4		14.6	ns
t_{LSU}	I/O Latch Set-Up	0.7		0.7		0.8		1.0		1.4		ns
t_{LH}	I/O Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t_{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9		8.8		10.0		11.8		16.5	ns

1. For dual-module macros, use $t_{PD1} + t_{RD1} + t_{PDn}$, $t_{CO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.
3. Data applies to macros based on the S-module. Timing parameters for sequential macros constructed from C-modules can be obtained from the Timer utility.
4. *Set-up and hold timing parameters for the Input Buffer Latch are defined with respect to the PAD and the D input. External setup/hold timing parameters must account for delay from an external PAD signal to the G inputs. Delay from an external PAD signal to the G input subtracts (adds) to the internal setup (hold) time.*
5. Delays based on 35 pF loading.

3.12 Pin Descriptions

This section lists the pin descriptions for 40MX and 42MX series FPGAs.

CLK/A/B, I/O Global Clock

Clock inputs for clock distribution networks. CLK is for 40MX while CLKA and CLKB are for 42MX devices. The clock input is buffered prior to clocking the logic modules. This pin can also be used as an I/O.

DCLK, I/ODiagnostic Clock

Clock input for diagnostic probe and device programming. DCLK is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

GND, Ground

Input LOW supply voltage.

I/O, Input/Output

Input, output, tristate or bidirectional buffer. Input and output levels are compatible with standard TTL and CMOS specifications. Unused I/Os pins are configured by the Designer software as shown in Table 46, page 84.

Table 46 • **Configuration of Unused I/Os**

Device	Configuration
A40MX02, A40MX04	Pulled LOW
A42MX09, A42MX16	Pulled LOW
A42MX24, A42MX36	Tristated

In all cases, it is recommended to tie all unused MX I/O pins to LOW on the board. This applies to all dual-purpose pins when configured as I/Os as well.

LP, Low Power Mode

Controls the low power mode of all 42MX devices. The device is placed in the low power mode by connecting the LP pin to logic HIGH. In low power mode, all I/Os are tristated, all input buffers are turned OFF, and the core of the device is turned OFF. To exit the low power mode, the LP pin must be set LOW. The device enters the low power mode 800 ns after the LP pin is driven to a logic HIGH. It will resume normal operation in 200 µs after the LP pin is driven to a logic LOW.

MODE, Mode

Controls the use of multifunction pins (DCLK, PRA, PRB, SDI, TDO). The MODE pin is held HIGH to provide verification capability. The MODE pin should be terminated to GND through a 10kΩ resistor so that the MODE pin can be pulled HIGH when required.

NC, No Connection

This pin is not connected to circuitry within the device. These pins can be driven to any voltage or can be left floating with no effect on the operation of the device.

PRA, I/O

PRB, I/OProbe A/B

The Probe pin is used to output data from any user-defined design node within the device. Each diagnostic pin can be used in conjunction with the other probe pin to allow real-time diagnostic output of any signal path within the device. The Probe pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality. The Probe pin is accessible when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

QCLKA/B/C/D, I/O Quadrant Clock

Quadrant clock inputs for A42MX36 devices. When not used as a register control signal, these pins can function as user I/Os.

SDI, I/OSerial Data Input

Serial data input for diagnostic probe and device programming. SDI is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW.

SDO, I/OSerial Data Output

Serial data output for diagnostic probe and device programming. SDO is active when the MODE pin is HIGH. This pin functions as an I/O when the MODE pin is LOW. SDO is available for 42MX devices only.

When Silicon Explorer II is being used, SDO will act as an output while the "checksum" command is run. It will return to user I/O when "checksum" is complete.

TCK, I/O Test Clock

Table 48 • **PL68**

PL68		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
24	I/O	I/O
25	VCC	VCC
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	GND	GND
33	I/O	I/O
34	I/O	I/O
35	I/O	I/O
36	I/O	I/O
37	I/O	I/O
38	VCC	VCC
39	I/O	I/O
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	I/O	I/O
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	GND	GND
50	I/O	I/O
51	I/O	I/O
52	CLK, I/O	CLK, I/O
53	I/O	I/O
54	MODE	MODE
55	VCC	VCC
56	SDI, I/O	SDI, I/O
57	DCLK, I/O	DCLK, I/O
58	PRA, I/O	PRA, I/O
59	PRB, I/O	PRB, I/O
60	I/O	I/O

Table 51 • **PQ144**

PQ144	
Pin Number	**A42MX09 Function**
43	I/O
44	GNDQ
45	GNDI
46	NC
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	I/O
53	I/O
54	VCC
55	VCCI
56	NC
57	I/O
58	I/O
59	I/O
60	I/O
61	I/O
62	I/O
63	I/O
64	GND
65	GNDI
66	I/O
67	I/O
68	I/O
69	I/O
70	I/O
71	SDO
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	GNDQ

Figure 43 • **PQ160**

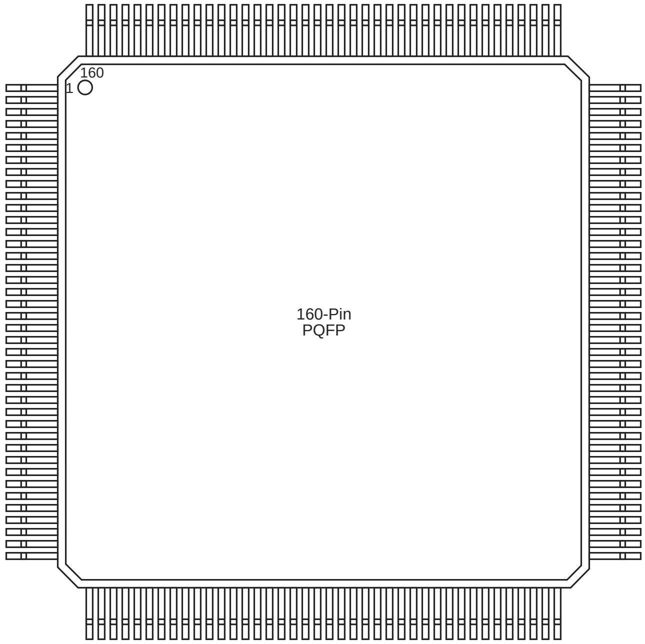


Table 52 • **PQ160**

PQ160			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
1	I/O	I/O	I/O
2	DCLK, I/O	DCLK, I/O	DCLK, I/O
3	NC	I/O	I/O
4	I/O	I/O	WD, I/O
5	I/O	I/O	WD, I/O
6	NC	VCCI	VCCI
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	NC	I/O	I/O
11	GND	GND	GND
12	NC	I/O	I/O
13	I/O	I/O	WD, I/O
14	I/O	I/O	WD, I/O
15	I/O	I/O	I/O
16	PRB, I/O	PRB, I/O	PRB, I/O
17	I/O	I/O	I/O
18	CLKB, I/O	CLKB, I/O	CLKB, I/O
19	I/O	I/O	I/O
20	VCCA	VCCA	VCCA

Table 52 • **PQ160**

PQ160			
Pin Number	**A42MX09 Function**	**A42MX16 Function**	**A42MX24 Function**
132	I/O	I/O	I/O
133	I/O	I/O	I/O
134	I/O	I/O	I/O
135	NC	VCCA	VCCA
136	I/O	I/O	I/O
137	I/O	I/O	I/O
138	NC	VCCA	VCCA
139	VCCI	VCCI	VCCI
140	GND	GND	GND
141	NC	I/O	I/O
142	I/O	I/O	I/O
143	I/O	I/O	I/O
144	I/O	I/O	I/O
145	GND	GND	GND
146	NC	I/O	I/O
147	I/O	I/O	I/O
148	I/O	I/O	I/O
149	I/O	I/O	I/O
150	NC	VCCA	VCCA
151	NC	I/O	I/O
152	NC	I/O	I/O
153	NC	I/O	I/O
154	NC	I/O	I/O
155	GND	GND	GND
156	I/O	I/O	I/O
157	I/O	I/O	I/O
158	I/O	I/O	I/O
159	MODE	MODE	MODE
160	GND	GND	GND

Figure 44 • **PQ208**

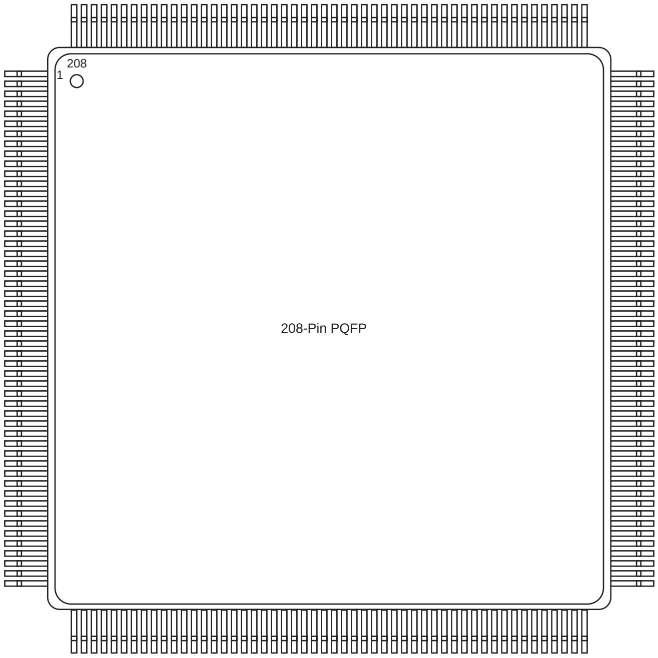


Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
1	GND	GND	GND
2	NC	VCCA	VCCA
3	MODE	MODE	MODE
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	NC	I/O	I/O
10	NC	I/O	I/O
11	NC	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	NC	I/O	I/O
17	VCCA	VCCA	VCCA
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O

Table 53 • **PQ208**

PQ208			
Pin Number	**A42MX16 Function**	**A42MX24 Function**	**A42MX36 Function**
58	I/O	WD, I/O	WD, I/O
59	I/O	I/O	I/O
60	VCCI	VCCI	VCCI
61	NC	I/O	I/O
62	NC	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	QCLKA, I/O
66	I/O	WD, I/O	WD, I/O
67	NC	WD, I/O	WD, I/O
68	NC	I/O	I/O
69	I/O	I/O	I/O
70	I/O	WD, I/O	WD, I/O
71	I/O	WD, I/O	WD, I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	GND	GND	GND
79	VCCA	VCCA	VCCA
80	NC	VCCI	VCCI
81	I/O	I/O	I/O
82	I/O	I/O	I/O
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	WD, I/O	WD, I/O
86	I/O	WD, I/O	WD, I/O
87	I/O	I/O	I/O
88	I/O	I/O	I/O
89	NC	I/O	I/O
90	NC	I/O	I/O
91	I/O	I/O	QCLKB, I/O
92	I/O	I/O	I/O
93	I/O	WD, I/O	WD, I/O
94	I/O	WD, I/O	WD, I/O

Table 55 • **VQ80**

VQ80		
Pin Number	**A40MX02 Function**	**A40MX04 Function**
49	I/O	I/O
50	CLK, I/O	CLK, I/O
51	I/O	I/O
52	MODE	MODE
53	VCC	VCC
54	NC	I/O
55	NC	I/O
56	NC	I/O
57	SDI, I/O	SDI, I/O
58	DCLK, I/O	DCLK, I/O
59	PRA, I/O	PRA, I/O
60	NC	NC
61	PRB, I/O	PRB, I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	I/O	I/O
68	GND	GND
69	I/O	I/O
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	VCC	**VCC**
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O

Table 60 • **BG272**

BG272	
Pin Number	**A42MX36 Function**
A6	I/O
A7	WD, I/O
A8	WD, I/O
A9	I/O
A10	I/O
A11	CLKA
A12	I/O
A13	I/O
A14	I/O
A15	I/O
A16	WD, I/O
A17	I/O
A18	I/O
A19	GND
A20	GND
B1	GND
B2	GND
B3	DCLK, I/O
B4	I/O
B5	I/O
B6	I/O
B7	WD, I/O
B8	I/O
B9	PRB, I/O
B10	I/O
B11	I/O
B12	WD, I/O
B13	I/O
B14	I/O
B15	WD, I/O
B16	I/O
B17	WD, I/O
B18	I/O
B19	GND
B20	GND
C1	I/O
C2	MODE

Table 62 • **CQ172**

99	I/O
100	I/O
101	I/O
102	I/O
103	GND
104	I/O
105	I/O
106	VKS
107	VPP
108	GND
109	VCCI
110	VSV
111	I/O
112	I/O
113	VCC
114	I/O
115	I/O
116	I/O
117	I/O
118	GND
119	I/O
120	I/O
121	I/O
122	I/O
123	GNDI
124	I/O
125	I/O
126	I/O
127	I/O
128	I/O
129	I/O
130	I/O
131	SDI
132	I/O
133	I/O
134	I/O
135	I/O
136	VCCI
137	I/O